

•General Description

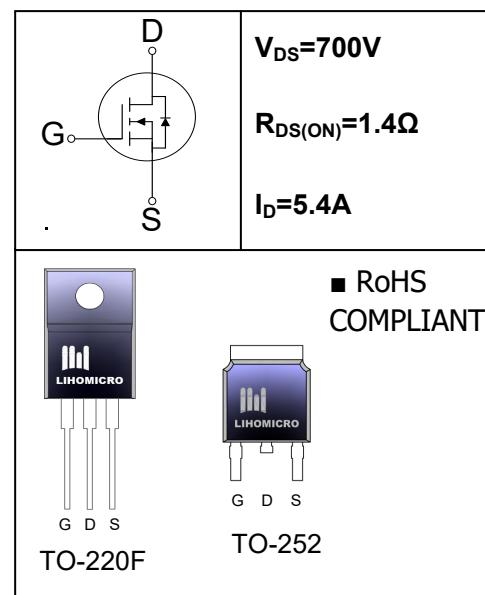
The SJ MOSFET LH70R1K6 has the low $R_{DS(on)}$, low gate charge, fast switching and excellent avalanche characteristics. This device offers extremely fast and robust body diode, and is suitable for telecom and power supplies.

•Features

- Much lower $R_{DS(on)} \cdot A$ performance for On-state efficiency
- Much lower FOM for fast switching efficiency

•Application

- LED/LCD/PDP TV and monitor Lighting
- Solar/Renewable/UPS-Micro Inverter System
- Power Supplies



•Ordering Information:

Part number	LH70R1K6	LH70R1K6
Package	TO-252	TO-220F
Basic ordering unit (pcs)	2500	1000
Normal Package Material Ordering Code	LH70R1K6T5-T0252-TAP	LH70R1K6F-T0220F-TU
Halogen Free Ordering Code	LH70R1K6T5-T0252-TAP-HF	LH70R1K6F-T0220F-TU-HF

•Absolute Maximum Ratings (TC = 25°C)

PARAMETER	SYMBOL	Value	UNIT
Drain-Source Breakdown Voltage	BV _{DSS}	700	V
Gate-Source Voltage	V _{GS}	±30	V
Continuous Drain Current TC = 25°C TC = 100°C	I _D	5.4	A
		3.4	
Pulsed drain current (TC = 25°C, tp limited by Tjmax) ¹	I _D pulse	16.2	A
Single Pulse Avalanche Energy ²	E _{AS}	26	mJ
Power Dissipation(TC=25°C)	P _D	5.4	W
Reverse diode dv/dt ³	dv/dt	15	V/ns
Maximum diode commutation speed ³	di/dt	50	V/ns
Operating Temperature and Storage Temperature Range	T _J /T _{STG}	-55~+150	°C

• Electronic Characteristics

PARAMETER	SYMBOL	TEST CONDITION	MIN	TYP	MAX	UNIT
Drain-Source Breakdown Voltage	BV_{DSS}	$V_{GS} = 0V, I_D = 250\mu A$	700	--	--	V
Gate Threshold Voltage	$V_{GS(TH)}$	$V_{DS} = V_{GS}, I_D = 250\mu A$	2.0	3.0	4.0	V
Drain-source On Resistance ³	$R_{DS(ON)}$	$V_{GS} = 10V, I_D = 2.4A$	--	1.4	1.6	Ω
Drain-Source Leakage Current	I_{DSS}	$V_{DS} = 700V, V_{GS} = 0V, T_J = 25^\circ C$	--	--	1	uA
		$V_{DS} = 700V, V_{GS} = 0V, T_J = 125^\circ C$	--	--	100	
Gate-Source Leakage Current	I_{GSS}	$V_{GS} = \pm 30$	--	--	± 100	A
Gate Resistance	R_G	$V_{GS} = 0V, f = 1.0MHz$	--	24	--	Ω
Input Capacitance	C_{iss}	$V_{GS} = 0V, V_{DS} = 250V, f = 1.0MHz$	--	225	--	pF
Output Capacitance	C_{oss}		--	300	--	
Reverse transfer Capacitance	C_{rss}		--	12	--	
Turn-on delay time	$T_d(on)$	$V_{DD} = 350V, I_D = 5.4A, R_G = 25\Omega$	--	11	--	
Turn -Off Delay Time	$T_d(off)$		--	30	--	
Rise time	T_r		--	25	--	ns
Fall time	T_f		--	24	--	
Total Gate Charge	Q_g	$I_D = 5.4A, V_{DS} = 560V, V_{GS} = 10V$	--	6.1	--	nC
Gate-to-Source Charge	Q_{gs}		--	1.3	--	
Gate-to-Drain Charge	Q_{gd}		--	3.3	--	
Continuous Diode Forward Current	I_s	--	--	--	5.4	A
Pulsed Diode Forward Current ¹	I_{SM}	--	--	--	23	A
Diode Forward Voltage	V_{SD}	$T_J = 25^\circ C, I_s = 5.4A, V_{GS} = 0V$	--	--	1.4	V
Reverse Recovery Time	t_{rr}	$V_{RR} = 100V, I_f = I_s, dI_f/dt = 100A/\mu s$	--	358	--	ns
Reverse Recovery Charge	Q_{rr}		--	1.5	--	uC

• Thermal Characteristics

PARAMETER	SYMBOL	MAX	UNIT
Thermal Resistance Junction-case	R_{thJC}	23	$^\circ C/W$
Thermal Resistance Junction-ambient	R_{thJA}	75	$^\circ C/W$

Notes:

1. Repetitive Rating: Pulse width limited by maximum junction temperature.

 2. $I_{AS} = 3.4A, V_{DD} = 50V, R_G = 25\Omega$, Starting $T_J = 25^\circ C$

 3. Pulse Test : Pulse width $\leq 300\mu s$, Duty cycle $\leq 2\%$

•Typical Characteristics ($T_J=25^\circ\text{C}$,unless otherwise noted)

Figure 1. Output Characteristics

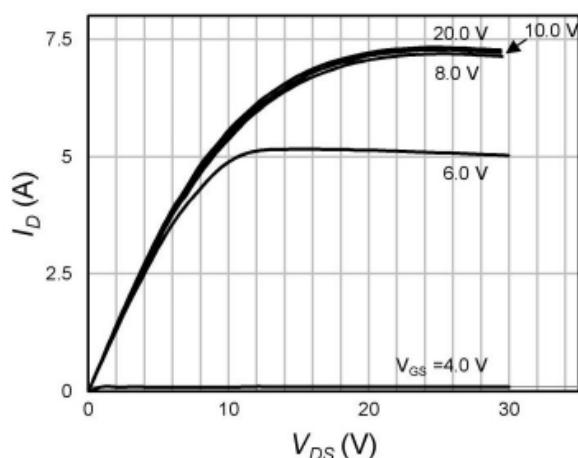


Figure 2.Drain-Souce On- State Resistance v.s. Drain Current

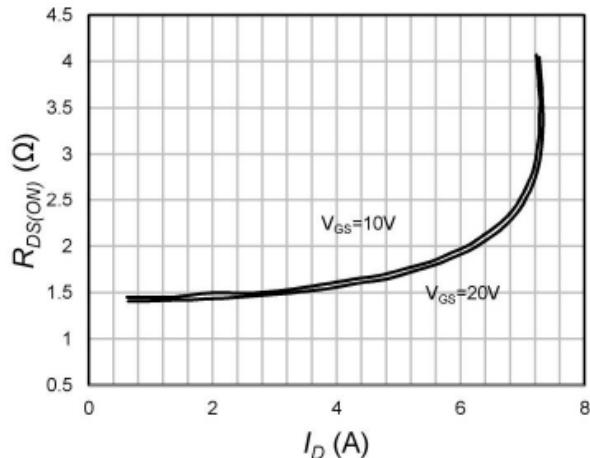


Figure 3. Capacitance

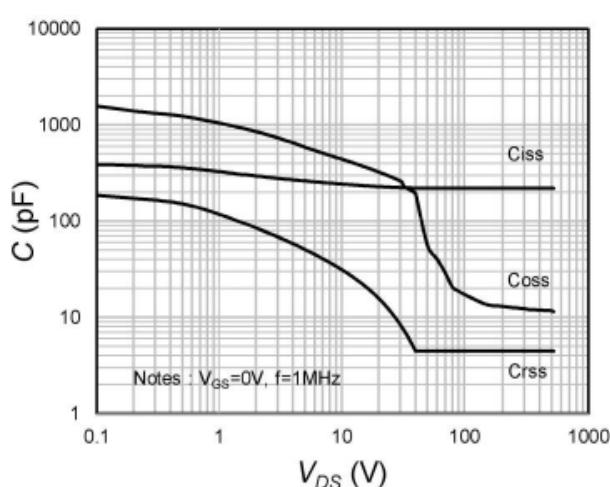


Figure 4.Drain-Souce Breakdown Voltage(Normalized)

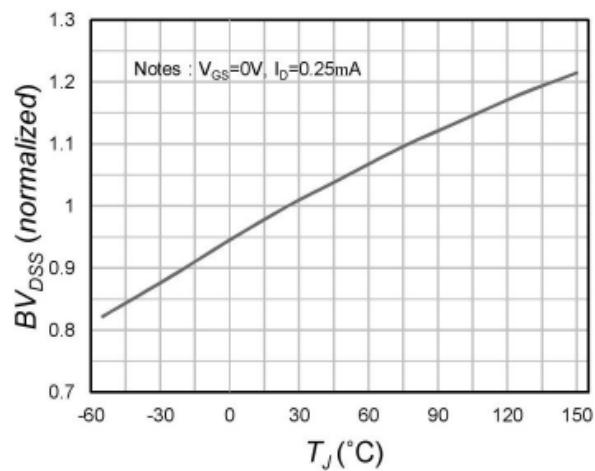


Figure 5. Transfer Characteristics

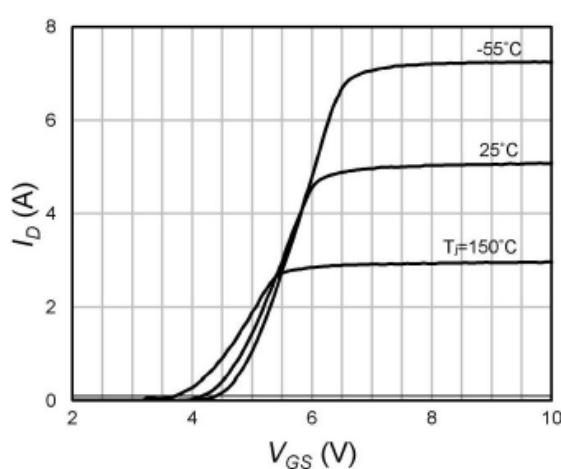
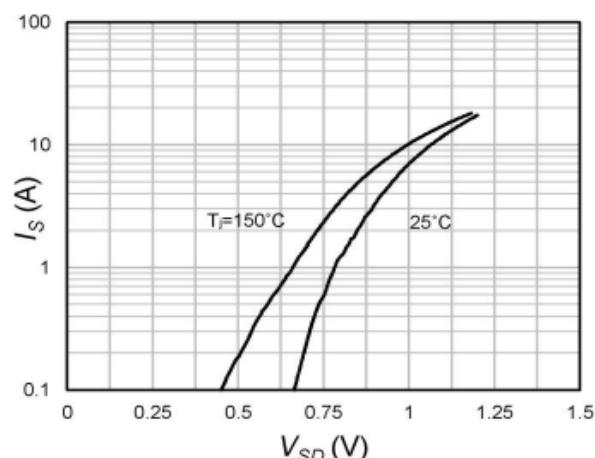
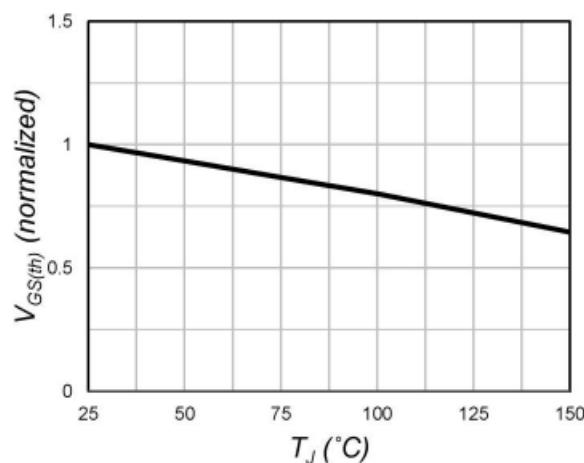
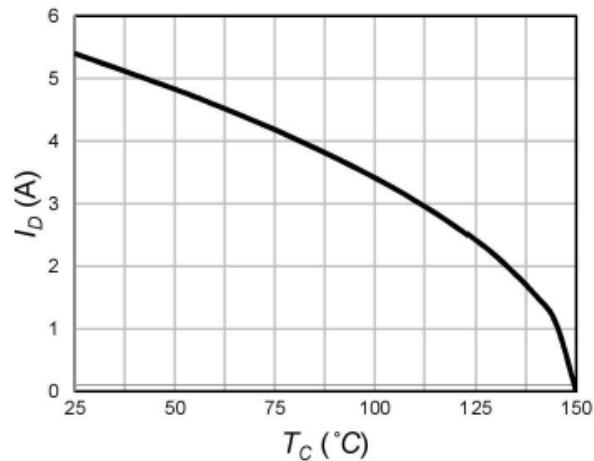
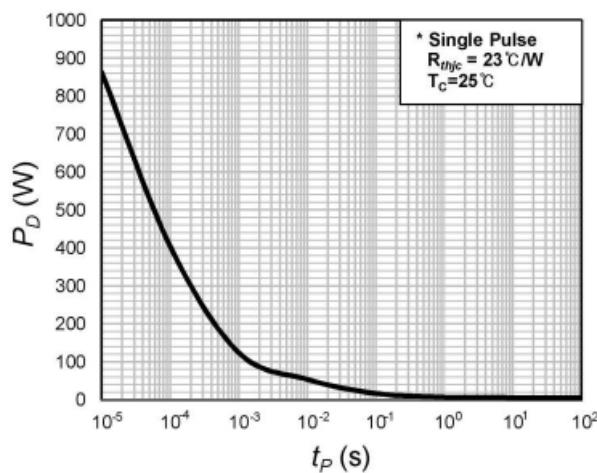
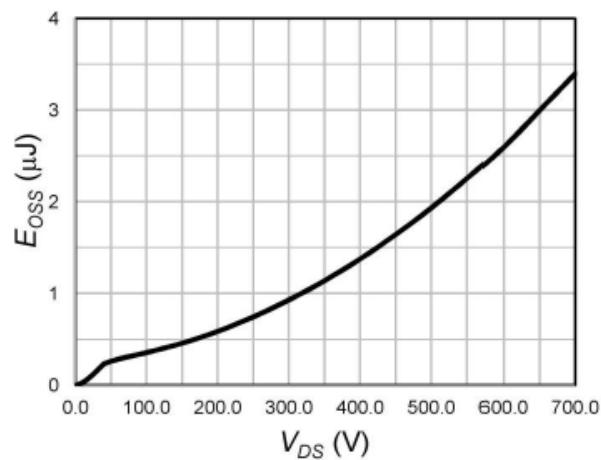
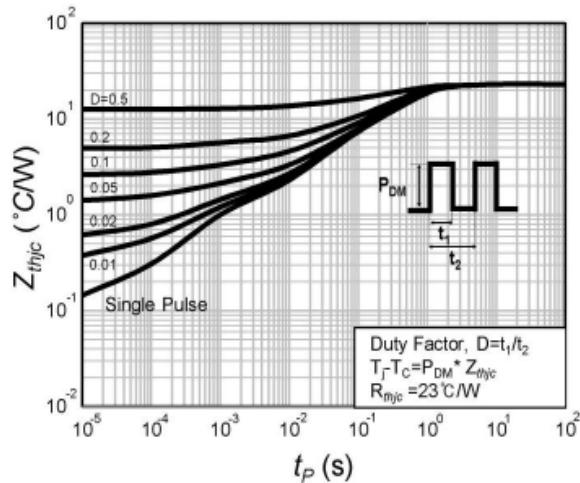
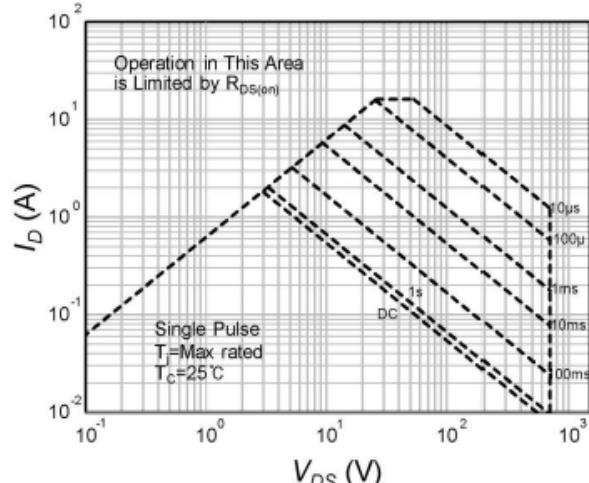


Figure 6. Forward Characteristics v.s. Reverse Diode



•Typical Characteristics (Cont.)
Figure 7.V_{gs(th)} V.S. Temprature

Figure 8.Max. Drain Current V.S. Case Temprature

Figure 9.Power Dissipation

Figure 10.Output Capacitance Stored Energy

Figure 11. Transient Thermal Impedance

Figure 12. Safe operation area


- Test Circuit and Waveforms

Figure A: Gate Charge Test Circuit and Waveform

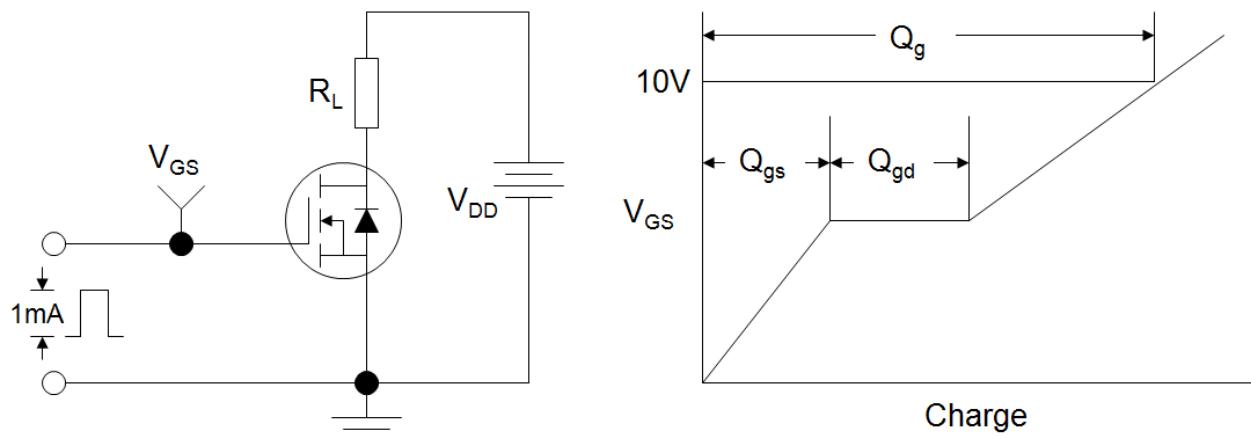


Figure B: Resistive Switching Test Circuit and Waveform

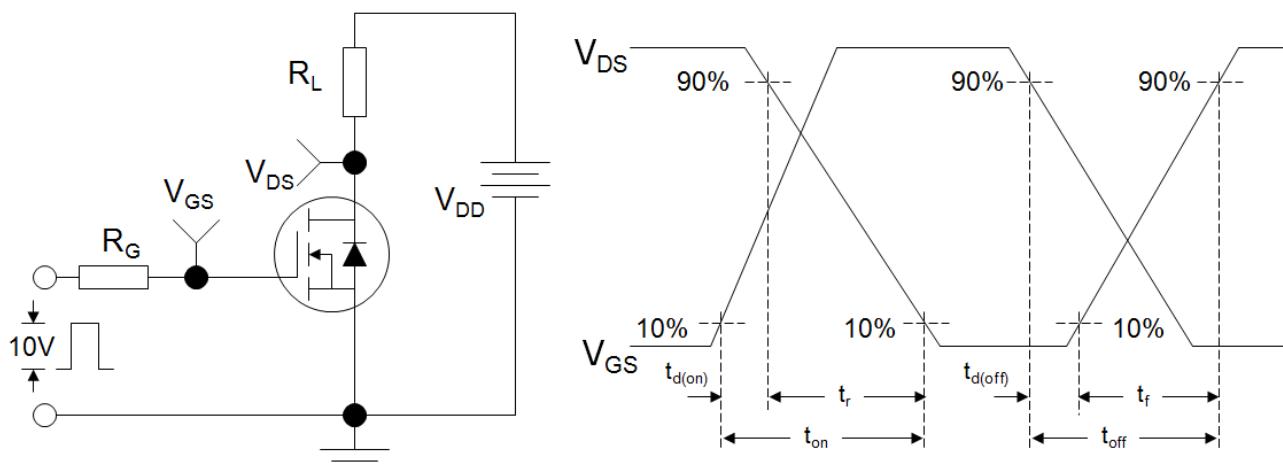
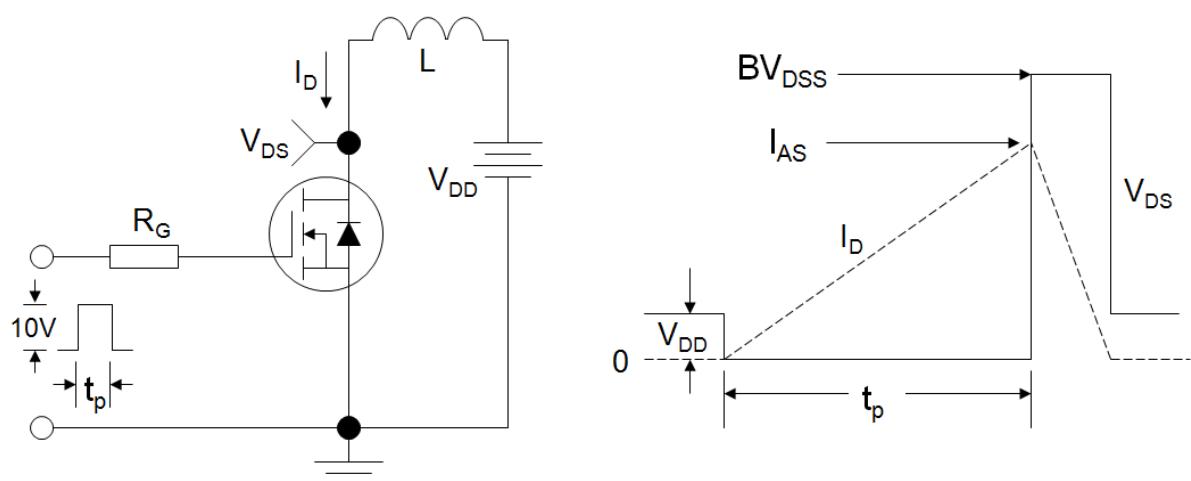


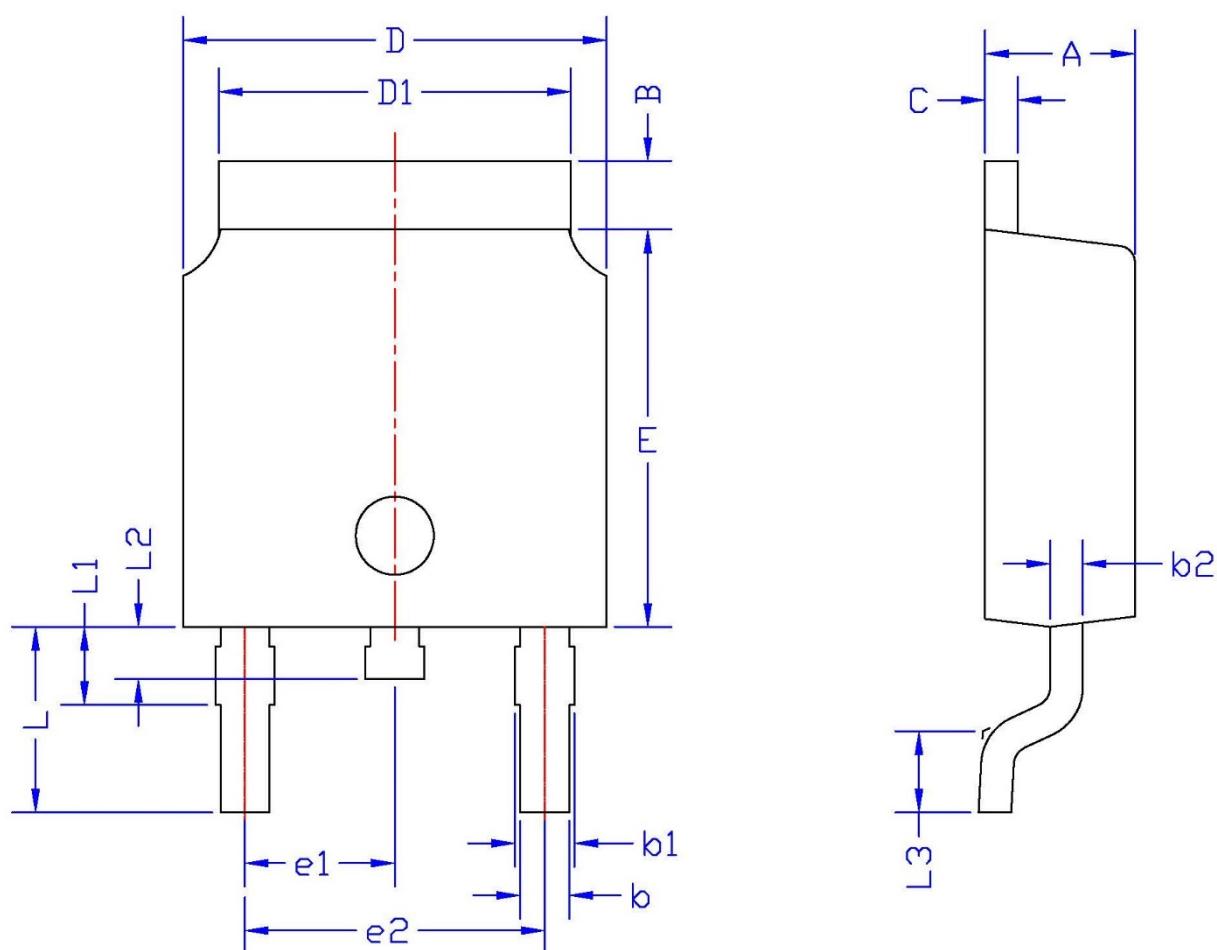
Figure C: Unclamped Inductive Switching Test Circuit and Waveform



•Dimensions (TO-252)

UNIT:mm

SYMBOL	min	max	SYMBOL	min	max
A	2.10	2.50	L2	0.60	1.20
b	0.50	0.90	L3	1.20	1.80
b1	0.70	1.20	B	0.80	1.30
b2	0.40	0.70	C	0.40	0.70
D	6.20	6.80	D1	5.10	5.60
E	5.80	6.40	e1	2.10	2.45
L	3.60	4.60	e2	4.40	4.80
L1	0.80	1.60			



•Dimensions (TO-220F)

UNIT:mm

SYMBOL	min	max	SYMBOL	min	max
A	4.20	4.80	E1	8.30	8.70
A1	2.50	2.90	e	2.40	2.70
A2	2.90	3.30	e1	4.95	5.25
b	0.40	0.80	F	2.50	2.90
b1	1.10	1.50	L	13.00	14.00
c	0.50	0.70	L1	3.00	4.00
D	9.80	10.60	ØP	2.90	3.50
E	14.60	15.60			

